

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/564,633 | | Applicant(s)/Patent Under Reexamination WATANABE ET AL. | |
| | Examiner Betelhem Shewareged | | Art Unit 1794 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-6,495,242 B1 | 12-2002 | Tsuchiya et al. | 428/32.24 |
| * | B | US-6,187,430 B1 | 02-2001 | Mukoyoshi et al. | 428/331 |
| * | C | US-2001/0009712 A1 | 07-2001 | TOTANI et al. | 428/195 |
| * | D | US-2002/0094421 A1 | 07-2002 | Quintens et al. | 428/195 |
| * | E | US-6,387,473 B1 | 05-2002 | Sismondi et al. | 428/32.34 |
| * | F | US-2003/0072925 A1 | 04-2003 | Kiyama et al. | 428/195 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | WO 02/34541 A1 | 05-2002 | PCT | Kiyama et al. | B41M 5/00 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.